

Design-for-Reliability and Accelerated Testing of Electronic and Photonic Products: What Should Be Done Differently

Ephraim Suhir,

Bell Laboratories, Portland State University and ERS Co., USA,

Microelectronics Workshop, June 1 - 3, 2016

Sabanci University, Istanbul-Turkey.



Ephraim Suhir is Distinguished Member of Research Staff, Bell Labs, Murray Hill, NJ (ret), and is currently on the faculty of the Portland State University, Portland, OR, USA, and Technical University, Vienna, Austria. He is also CEO of the Small Business Innovative Research (SBIR) ERS Co. in Los Altos, CA, USA. Ephraim is Foreign Full Member (Academician) of the Academy of Engineering, Ukraine (he was born in that country); IEEE Life Fellow; Fellow of the American Physical Society (APS), the American Society of Mechanical Engineers Society of Mechanical Engineers (ASME), the Institute of Physics (IoP), UK, the Society of Optical Engineers (SPIE), the International Society of Microelectronics and Packaging (IMAPS), the Society of Plastics Engineers (SPE), and Associate Fellow of the American Institute of Aeronautics and Astronautics (AIAA). Dr. Suhir has authored about 380 publications (patents, technical papers, book chapters, books), presented numerous keynote and invited talks worldwide, and received many professional awards, including 2004 ASME Worcester Read Warner Medal for outstanding contributions to the permanent literature of engineering (he is the third Russian American, after S. Timoshenko and I. Sikorsky, who received this prestigious award); and 1996 Bell Laboratories Distinguished Member of Technical Staff Award for developing methods for predicting the reliability of complex structures used in manufacturing AT&T and Lucent Technologies products.